## Notice of R ferenc s Cited

Application/Control No.

10/760,353

Applicant(s)/Patent Under Reexamination TOYOMURA ET AL.

Examiner

Y. J. Han

Art Unit
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## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-5,616,968	04-1997	Fujii et al.	307/66
	В	US-			
	C	US-			
	D	US-			
	Е	US-			
	F	US-			*****
	G	US-			
	Τ	US-			
	_	US-			
	7	US-			
	Κ	US-			
	L	US-			
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## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	Q					
	R					
	S					
	Т					

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)	
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